

**AMENDMENTS TO THE CLAIMS:**

This listing of claims will replace all prior versions, and listings, of claims in the application:

**LISTING OF CLAIMS:**

1-17. (Canceled).

18. (Currently Amended) A [[The]] method as recited in claim 17 for monitoring an operating readiness of two memory elements assigned to an electronic unit, comprising: monitoring a supply voltage of the electronic unit; operating each of the memory elements using a respective operating voltage that is different compared to the supply voltage, each of the operating voltages being in a specified range so that the respective memory element is operational; and detecting, based on the monitoring of the supply voltage, that the operating voltage of one of the two memory elements is not in the specified range, and processing program code from the other of the two memory elements whose operating voltage is in the specified range;  
wherein the monitoring of the supply voltage includes initially dividing down the supply voltage.

19. (Previously Presented) The method as recited in claim 18, wherein the monitoring of the supply voltage includes cyclically measuring the divided down supply voltage using an analog-digital converter.

20. (Previously Presented) The method as recited in claim 18, wherein the monitoring of the supply voltage includes cyclically reading in the divided down supply voltage at a general purpose input of an electronic computing unit.

21. (Previously Presented) The method as recited in claim 18, wherein the monitoring of the supply voltage includes analyzing the divided down supply voltage at an interrupt input of an electronic computing unit.

22. (Previously Presented) The method as recited in claim 19, wherein the monitoring of the supply voltage includes entering the supply voltage into a comparator whose output signal is analyzed.

23. (Previously Presented) The method as recited in claim 22, wherein the monitoring of the supply voltage includes cyclically reading in the output signal of the comparator at a general purpose input of an electronic computing unit.

24. (Previously Presented) The method as recited in claim 22, wherein the monitoring of the supply voltage includes analyzing the output signal of the comparator at an interrupt input of an electronic computing unit.

25. (Currently Amended) A [[The]] method as recited in claim 17 for monitoring an operating readiness of two memory elements assigned to an electronic unit, comprising:

monitoring a supply voltage of the electronic unit;

operating each of the memory elements using a respective operating voltage that is different compared to the supply voltage, each of the operating voltages being in a specified range so that the respective memory element is operational;

monitoring the operating voltage of [[the]] at least one of the memory elements; and detecting, at least based on the monitoring of the supply voltage, that the operating voltage of one of the two memory elements is not in the specified range, and processing program code from the other of the two memory elements whose operating voltage is in the specified range.

26. (Currently Amended) An electronic unit that is using a supply voltage, comprising:

two memory elements assigned to the electronic unit, each of the memory elements being operated using an operating voltage that is different than the supply voltage, each of the operating voltages being in a respective, specified range so that the respective memory element is operational; and

a monitor to monitor the supply voltage, wherein the electronic unit is adapted for detecting, based on the monitoring of the supply voltage, ~~when the electronic unit detects~~ that the operational voltage of one of the two memory elements is no longer in its respective specified range [[,]] and to responsively cause program code [[is]] to be processed from the other of the two memory element when elements whose operating voltage is in its respective specified range;

wherein the monitoring of the supply voltage includes initially dividing down the supply voltage.

27. (Previously Presented) The electronic unit as recited in claim 26, further comprising:

an electronic computing unit.

28. (Previously Presented) The electronic unit as recited in claim 26, wherein at least one of the memory elements is a flash memory element.

29. (Previously Presented) The electronic unit as recited in claim 26, wherein the monitor includes an analog-digital converter to monitor the supply voltage.

30. (Previously Presented) The electronic unit as recited in claim 26, wherein the monitor includes a comparator to monitor the supply voltage.

31. (Canceled).

32. (Currently Amended) A computer readable ~~[[data]]~~ medium having stored thereon instructions executable by a processor, the instructions which, when executed, cause the processor to perform a method for monitoring ~~storing a computer program, the computer program including: program code configured to be executed on a computing unit, the program code configured to monitor~~ an operational readiness of two memory elements assigned to an electronic unit, the method resulting in performance of program code, when executed by the computer unit, causing the computing unit to perform the following steps:

monitoring a supply voltage of the electronic unit;

operating each of the memory elements using ~~[[an]]~~ a respective operating voltage that is different compared to the supply voltage, each of the operating voltages being in a specified range so that the respective memory element is operational; and

detecting, based on the monitoring of the supply voltage, that the operating voltage of one of the two memory elements is not in the specified range, and processing program code from the other ~~[[are]]~~ of the two memory elements whose operating voltage is in the specified range;

wherein the monitoring of the supply voltage includes initially dividing down the supply voltage.